

Nanoindentation and plasticity in nanocrystalline Ni nanowires: A case study in size effect mitigation

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We examine the processes of spherical indentation and tension in Ni nanowires and thin films containing random distributions of nanoscale grains by molecular dynamics simulations. It is shown that the resistance to nanoindentation of nanocrystalline Ni nanowires with diameters of 12 and 30 nm tends not to depend on the wire diameter and free surfaces, contrary to nanoindentation in single-crystalline nanowires. Accommodation of plastic deformation by grain boundary sliding suggests a mitigation strategy for sample boundary effects in nanoscale plasticity.

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The mechanical behavior of metallic nanowires (NWs) and micropillars (MPs) is found to exhibit a pronounced dependence on sample size, which does not exist with macroscopic properties in bulk metals [1–9]. In particular, pure tension and compression experiments in single-crystalline NWs and MPs made of face-centered cubic (fcc) metals, such as Ni and Au, have shown evidence for a drastic increase in plastic flow stress with a size reduction in the sub-micron regime; a phenomenon proving that “smaller is stronger” under tension or compression [1–7]. On the contrary, nanoindentation studies in single-crystal fcc MPs and NWs [10–13] have revealed a decrease in Young’s modulus and hardness as the specimen size decreases; thus leading to an inverse scaling behavior where smaller NWs appear less resistant to contact loads than thicker ones. Therefore, the loading modes resulting from different characterization techniques strongly influence the study of size effects on strength and plasticity in NWs. The softening behavior observed during nanoindentation of single-crystal NWs can be interpreted by sample boundary effects on crystal plasticity, where the interaction of lattice dislocations emitted beneath the contacting tip, and their easy absorption by free surfaces, become more frequent and predominant as the sample diameter decreases [12]. Since metallic NWs are basic building blocks at the

nanoscale level in electronic and electromechanical devices, it is critically important to alleviate such inverse size effects on plastic flow in fcc metal NWs when subjected to nanoindentation.

In this paper, we report on a possible mitigation strategy for sample boundary effects in metallic NWs under nanoindentation when NWs are nanostructured with a random distribution of nanoscale grains smaller than the wire diameter. Molecular dynamics (MD) simulations are used to gain fundamental insight into the processes of nanoindentation and pure tension in nanocrystalline Ni NWs with a mean grain size of 7 nm. This type of metallic NW is representative of realistic fcc metal NWs that can readily be produced with polycrystalline microstructures during synthesis [14,15]. Simulations in thin Ni films with identical grain size were also performed to study the intrinsic effect of free surfaces in the indentation of nanocrystalline Ni NWs. Here, we show a phenomenon of size invariance in the resistance to nanoindentation of nanocrystalline Ni NWs, in stark contrast to nanoindentation in single-crystalline NWs. The mechanisms of plasticity in deformed nanocrystalline Ni NWs are analyzed at atomic level by using least-squares atomic local shear strain invariant calculations [16] in order to explain this effect.

Simulations of deformation in NWs and thin films by nanoindentation with a frictionless, spherical tip, as well as by pure tensile loading, were performed by MD using an embedded-atom method (EAM) following the methodologies described in earlier work by Sansoz and co-

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workers [12,17]. In this study, we used an EAM interatomic potential for Ni from Mishin et al. [18]. The NWs were 40 nm in length, with diameters of 12 and 30 nm as shown in the inset of Figure 1. Periodic boundary conditions were applied along the wire axis to model an infinitely long NW. To simulate thin films, the whole simulation box (40×40 nm) was filled with atoms and periodic boundary conditions were applied to the directions parallel to the film surface. The film thicknesses were equal to the two NW diameters studied, i.e. 12 and 30 nm. Both thin film and NW models were constructed with a random distribution of grains with a mean size of 7 nm using a 3D Voronoi tessellation technique and an arbitrary crystal orientation [19]. The number of atoms ranged from ~ 0.4 million (12 nm diameter NW) to 4.4 million (30 nm thick film). The simulations presented in this work required $\sim 25,000$ computer processing unit (CPU) hours. Prior to deformation, all models were relaxed in two steps. First, we performed an energy minimization with a conjugate gradient method. Second, a zero stress relaxation in the isothermal-isobaric ensemble (constant number of particles, pressure and temperature, NPT) using a Nosé–Hoover thermostat was performed at 300 K for 125 ps (25,000 steps). The time step was 5 fs. Deformation was subsequently carried out at the same temperature in the canonical ensemble (constant number of particles, volume and temperature, NVT). To simulate the process of nanoindentation, the bottom two atomic

layers were fixed in all directions to enable tip penetration into the specimens, while preventing rolling or sliding during deformation. The tip was modeled as a virtual sphere of 18 nm in diameter by a repulsive force with a force constant equal to 10 N m^{-2} [12,20–22]. A gap of 0.2 nm was initially imposed between the sample surface and the tip. The tip was displaced at a rate of 1 m s^{-1} . The final depth of indentation into the samples was 1.8 nm (400,000 steps). The atomic positions were recorded at 10 ps intervals (2000 steps). The contact zone was defined by the atoms positioned within the boundary of the virtual indenter. The mean contact pressure was calculated by dividing the total force on the indenter by the projected area of contact determined directly from the contacted atom positions. To simulate pure tensile deformation, the NWs were deformed by straining the simulation box along the wire axis at a constant engineering strain rate of $5 \times 10^7 \text{ s}^{-1}$. The mechanisms of plastic deformation were analyzed quantitatively by calculating the least-squares atomic local shear strain invariant [16] in the atomistic configuration viewer AtomEye [23]. In this paper, atoms in dark color are atoms undergoing negligible plastic deformation, while atoms in severely deformed zones with more than 30% plastic deformation appear in white color. As shown below, this visualization technique enables accurate detection of both intergranular and intragranular modes of plastic deformation in nanocrystalline solids.

The tensile behavior of the two nanocrystalline Ni NWs investigated is represented in Figure 1. For both NWs, the figure shows no sharp yielding point. Instead, the behavior becomes rapidly non-linear at an applied stress of ~ 1.3 GPa. This effect predominantly results from a localization of plastic deformation at grain boundaries, as shown in Figure 1b,c, where intense interface sliding is observed in all grain boundaries present in the models. The yield stress at 0.2% plastic strain is found equal to 1.45 and 1.69 GPa in the 12 and 30 nm NWs, and the maximum stress to 2.13 and 2.33 GPa, respectively. The lower overall flow stresses in the 12 nm NW as compared to the 30 nm NW in tension can be explained by the higher propensity to deform at grain boundaries due to free surface effects. Intergranular deformation is generally accompanied with serrated plastic flow [24], which is also more clearly evident in the stress–strain curve of the 12 nm diameter NW in Figure 1a, than in the curve for the 30 nm diameter NW. This result confirms earlier reports by Monk and Farkas [25,26] who have also used MD simulations to study the effect of diameter on the uniform deformation of nanocrystalline Ni NWs with mean grain sizes less than 10 nm. They found that the importance of dislocation-mediated plasticity decreases, while grain boundary sliding dramatically increases, in nanocrystalline NWs less than 36 nm in diameter and that such effect is more significant in tension than compression.

We now shift focus on the process of spherical indentation in NWs identical to those presented in Figure 1. Figure 2 shows different cross-sectional views of the 30 nm diameter NW deformed in its center by the virtual tip up to a penetration depth of 1.8 nm, which corresponds to a radial strain of 6% relative to the NW diameter. We observe in this case that the least-squares

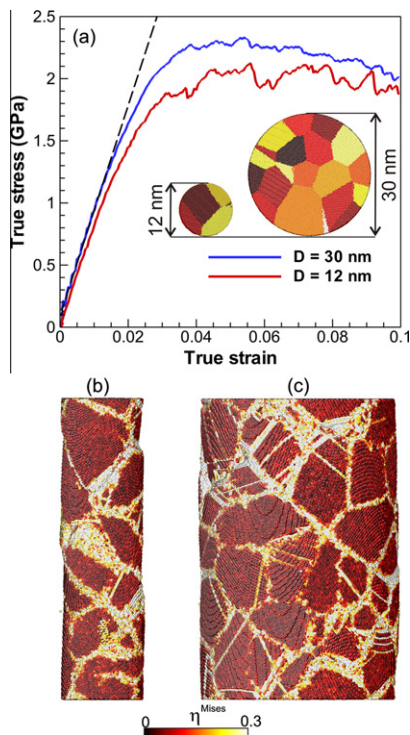


Figure 1. Molecular dynamics simulation of plasticity in nanocrystalline Ni nanowires under pure tension. (a) True stress–strain curves for 12 and 30 nm Ni nanowires with a mean grain size of 7 nm. Atomic-level snapshot at 10% deformation in Ni nanowires with a diameter equal to (b) 12 nm and (c) 30 nm. Coloring corresponds to the least-squares atomic local shear strain invariant (η^{Mises}), which shows that more plastic deformation is accommodated by grain boundary sliding than by the propagation of lattice dislocations.

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